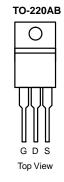


COMPLIANT

### HM70P04-VB Datasheet

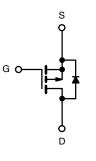
## P-Channel 40-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V <sub>DS</sub> (V)	r <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
- 40	0.0041 at V <sub>GS</sub> = - 10 V	- 110	185 nC



#### **FEATURES**

• TrenchFET<sup>®</sup> Power MOSFET



P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 40	v
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C		- 110 <sup>a</sup>	
Continuous Drain Current (T = $175 ^{\circ}$ C)	T <sub>C</sub> = 70 °C		- 110 <sup>a</sup>	
Continuous Drain Current ( $T_J = 175 \ ^\circ C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	39 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		33 <sup>b, c</sup>	
Pulsed Drain Current		I <sub>DM</sub>	240	A
Continuous Courses Drain Diada Current	T <sub>C</sub> = 25 °C	1	110	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	10 <sup>b, c</sup>	
Avalanche Current		I <sub>AS</sub>	75	
Single-Pulse Avalanche Energy L = 0.1 mH		E <sub>AS</sub>	281	mJ
	T <sub>C</sub> = 25 °C		375	
Maximum Davier Dissis ation	T <sub>C</sub> = 70 °C	Р	262	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	15 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		10.5 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C
Soldering Recommendations (Peak Temperature) <sup>d, e</sup>			260	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	8	10	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	0.33	0.4	

Notes:

a. Package limited.b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s. d. Maximum under Steady State conditions is 40 °C/W.

<b>SPECIFICATIONS</b> $T_J = 25 \text{ °C}$ , u	inless other	wise noted				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	•					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 40			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μΑ		- 40		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η = - 230 μΑ		- 5.5		mv/ c
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 2	- 3	- 4	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = -40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μΑ
		$V_{DS}$ = - 40 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5$ V, $V_{GS} = -10$ V	- 120			Α
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 20 A		0.0041		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 20 A		75		S
Dynamic <sup>b</sup>				•		
Input Capacitance	C <sub>iss</sub>			11300		
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		1510		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			1000		
Total Gate Charge	Qg			185	280	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = - 20 V, $V_{GS}$ = - 10 V, $I_{D}$ = - 110 A		48		nC
Gate-Drain Charge	Q <sub>gd</sub>			42		
Gate Resistance	R <sub>g</sub>	f = 1 MHz		4.0		Ω
Turn-On Delay Time	t <sub>d(on)</sub>			25	40	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 0.18 $\Omega$		290	440	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$\text{I}_\text{D}\cong$ - 110 A, $\text{V}_\text{GEN}$ = - 10 V, $\text{R}_\text{g}$ = 1 $\Omega$		110	165	
Fall Time	t <sub>f</sub>			35	55	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	ا <sub>S</sub>	T <sub>C</sub> = 25 °C			- 110	A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 240	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 20 A		- 0.8	- 1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			70	105	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 20 A, di/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		130	200	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$F = -20 \text{ A}, \text{ u/u} = 100 \text{ A/}\mu\text{s},  \text{I}_{\text{J}} = 25 \text{ C}$		37		
Reverse Recovery Rise Time	t <sub>b</sub>			33		ns

Notes:

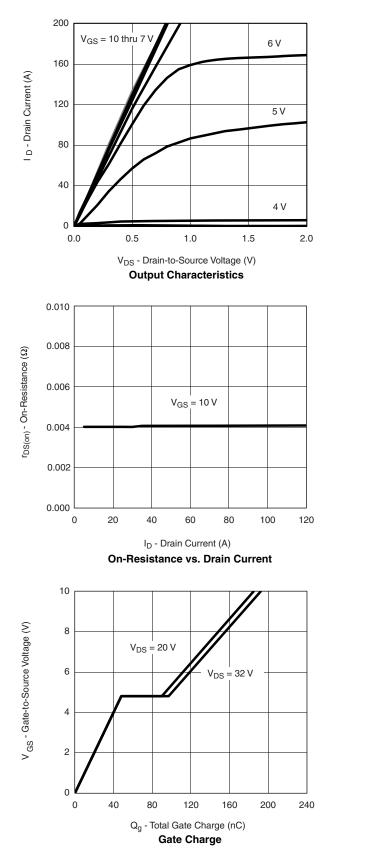
a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

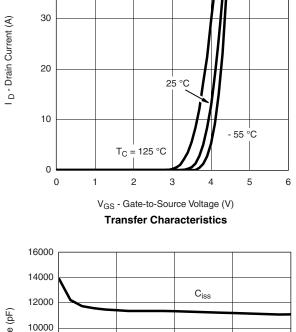
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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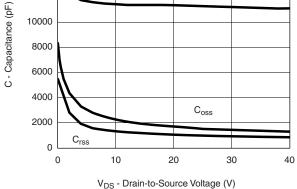




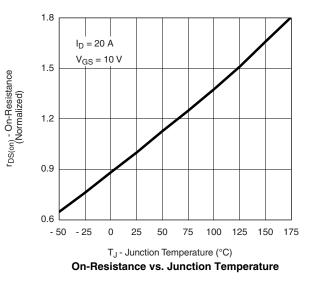
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



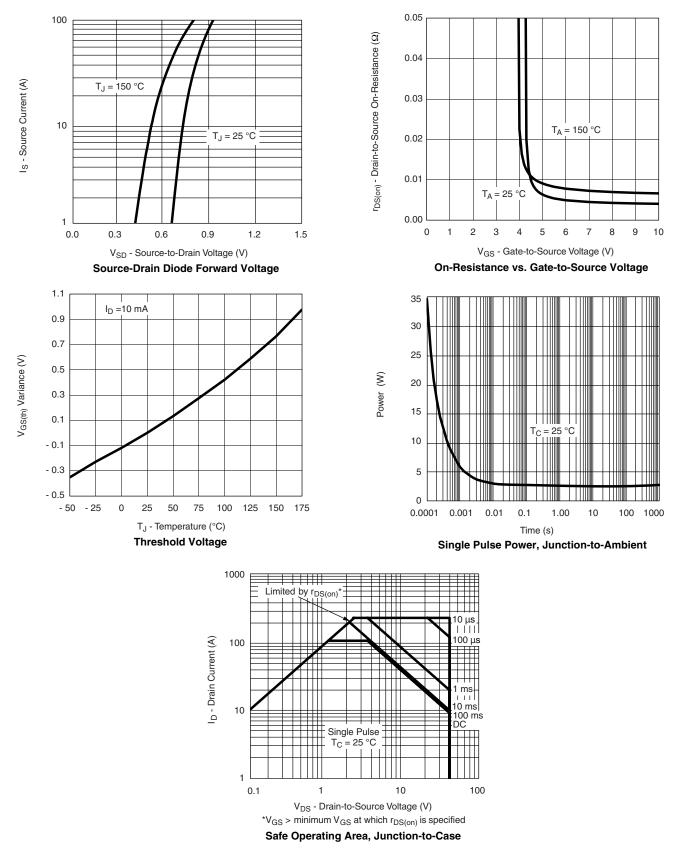
40



Capacitance

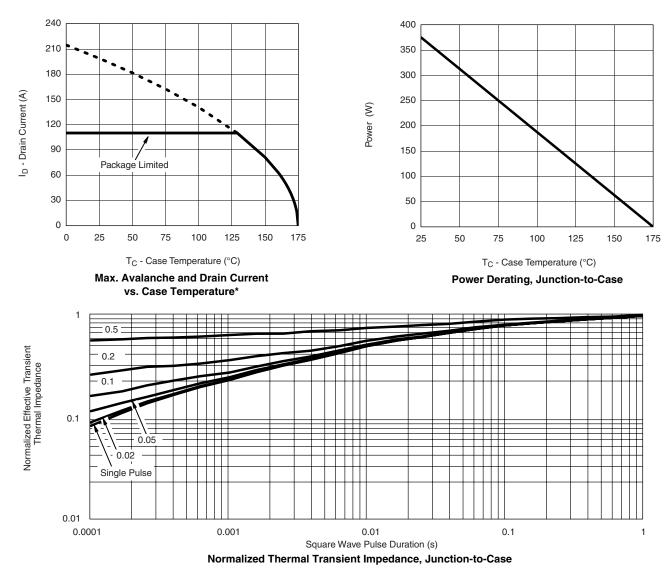






#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



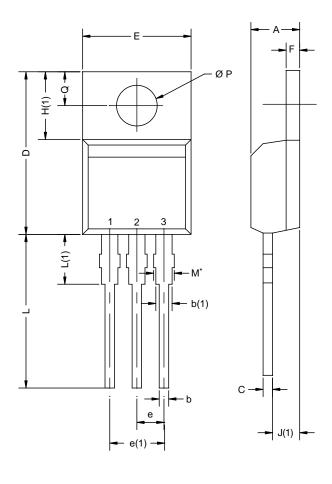


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



## **TO-220AB**



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		

#### Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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